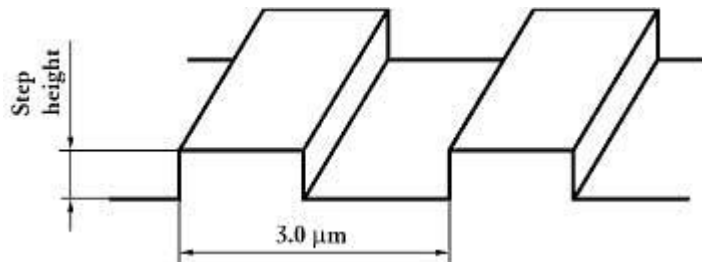
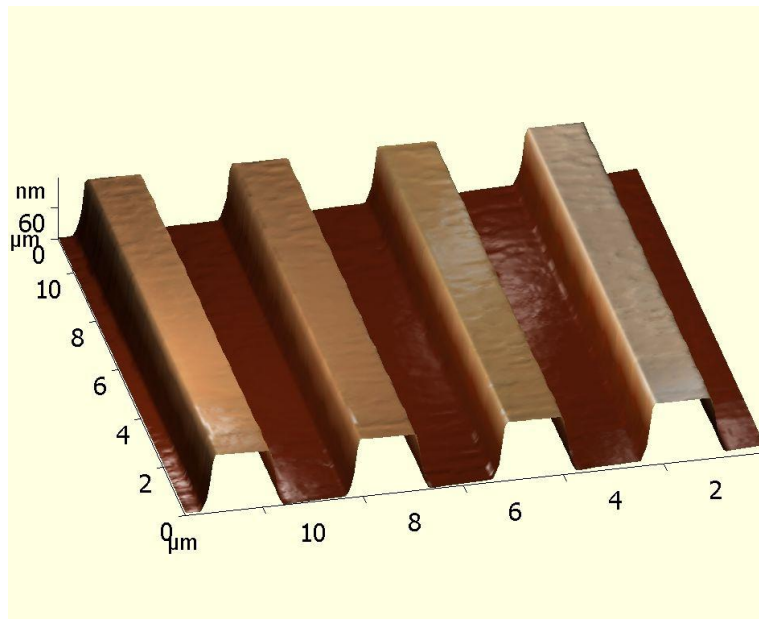


Product Description

Calibration grating TGZ2 is intended for Z-axis calibration (step height 110 ± 2 nm) and nonlinearity measurements.



* Step height is the average meaning based on the measurements of 5 gratings with the same height (from the batch of 300 gratings) by AFM calibrated with help of PTB certified grating TGZ1. Basic step height can vary from the specified one within ± 20 % depending on the batch (for example TGZ2 grating can have step height 95 ± 2 nm).



AFM image of TGZ2 grating (step height 110 nm).

General Features

Structure	step - SiO ₂ , bottom - Si
Pattern type	2-Dimensional
Period	$3 \pm 0,05$ μm
Height	110 ± 2 nm*
Chip size	5x5x0,5 mm
Effective area	central square 3x3 mm